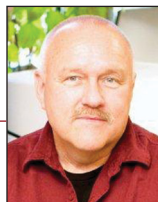


From the Editor



What a Year!!

With a title like “What a Year” most are probably thinking that this is yet another editorial about COVID. However, as I finish my first year as the Editor-in-Chief of *Microscopy Today* (MTO), I would like to recap some positive 2020 happenings for the Microscopy Society of America (MSA) publications and annual meeting. Despite the many problems associated with living during a pandemic, it is often good to think about the good things around us and that not all is gloom and doom.

First and foremost, after a full year under my leadership, I am happy to say that I have not totally messed up MTO and the outstanding magazine that Charles Lyman left to my care. This year we increased the number of pages published by 20%, and MTO now reaches 19,347 domestic and 2,350 international subscribers for a total of 21,697. In addition, through collaboration with Cambridge University Press, MTO is sent to 8,369 libraries. We also started educational webinars, and two successful events with TESCAN and 3D-Micromac were recently held. The 2nd annual Micrograph Competition, with entries from 20 states and 21 different countries, and the 11th annual Innovations Award Competition were also completed.

Our sister publication *Microscopy and Microanalysis* (MaM) also had a successful year highlighted by earning the highest impact factor (3.414) in its history. MaM is now ranked 114 out of 314 materials science/multidisciplinary journals and 2nd in microscopy journals.

M&M 2020, like other major meetings, was virtual. Even so there were 692 platform presentations, 451 poster presentations, and 2,990 online attendees. The article by Houlin Xin later in this issue provides additional details about M&M 2020. I am sure we are all hopeful for the end of the COVID pandemic so we can get back to our “normal” lives and once again attend on-site meetings. However, if we are forced to have another virtual meeting, Liz Wright, the M&M 2021 Program Chair has planned an exciting meeting with outstanding plenary speakers as detailed later in this issue.

The only way to continue the success of MSA is through your participation. Please submit articles to the publications, participate in the relevant competitions, attend the M&M 2021 meeting, and become a member of MSA.

Robert L. Price
Editor-in-Chief

Publication Objective: to provide information of interest to microscopists.

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